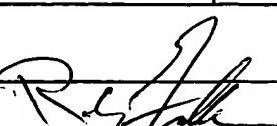




Form PTO 1449 (Modified) <b>U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE</b> <b>LIST OF REFERENCES CITED BY APPLICANT</b>				ATTY DOCKET NO. <b>219587US90</b>	SERIAL NO. <b>10/072,866</b>	
				<b>APPLICANT</b> <b>Masato HAMATANI, et al.</b>		
				<b>FILING DATE</b> <b>February 12, 2002</b>		<b>GROUP</b> <b>2851</b>
				<b>U.S. PATENT DOCUMENTS</b>		
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS SUB CLASS	
PT	AA	6,248,486	06/19/2001	DIRKSEN, et al.		
PT	AB	2002/0008869 A1	01/24/2002	VAN DER LAAN, et al.		
PT	AC	2002/0036758 A1	03/28/2002	DE MOL, et al.		
PT	AD	2002/0191165 A1	12/19/2002	BASELMANS, et al.		
PT	AE	5,978,085	11/02/1999	SMITH, et al.		
PT	AF	6,078,554	06/20/2000	OOTAKI, et al.		
PT	AG	6,118,535	09/12/2000	GOLDBERG, et al.		
PT	AH	6,100,978	08/08/2000	NAULLEAU, et al.		
PT	AI	2002/0001071 A1	01/03/2000	NOMURA, et al.		
PT	AJ	5,754,299	05/19/1998	SUGAYA, et al.		
PT	AK	6,329,112	12/11/2001	FUKUDA, et al.		
<b>FOREIGN PATENT DOCUMENTS</b>						
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES      NO	
PT	AK	1 160 626	12/05/2001	EUROPE		
PT	AL	WO 00/31592	06/02/2000	WIPO		
PT	AM	1 128 217	08/29/2001	EUROPE		
PT	AN	10-154657	06/09/1998	Japan (w/ English abstract)	x	
PT	AO	2000-121491	04/28/2000	Japan (w/ English abstract)	x	
PT	AP	WO 99/60361	11/25/1999	WIPO (w/ English abstract)	x	
PT	AQ	1 079 223	02/28/2001	EUROPE		
PT	AR	11-118613	04/30/1999	Japan (w/ English abstract)	x	
PT	AS	6-235619	08/23/1994	Japan (w/ English abstract)	x	
PT	AT	5-296879	11/12/1993	Japan (w/ English abstract)	x	
PT	AU	2000-47103	02/18/2000	Japan (w/ English abstract)	x	
PT	AV	2000-331923	11/30/2000	Japan (w/ English abstract)	x	
PT	AW	11-233424	08/27/1999	Japan (w/ English abstract)	x	
PT	AX	198 20 785 A1	10/21/1999	Germany	x	
PT	AY	2000-121491	04/28/2000	Japan (w/ English abstract and translation)	x	
PT	AZ	2000-146757	05/26/2000	Japan (w/ English abstract and machine translation)	x	
PT	BA	2000-266640	09/29/2000	Japan (w/ English abstract and machine translation)	x	
PT	BB	WO 00/55890	09/21/2000	WIPO (w/ English abstract)	x	
PT	BC	2001-230193	08/24/2001	Japan (w/ English abstract and machine translation)	x	
PT	BD	1 160 626 A1	12/05/2001	Europe		
PT	BF	1 355 140 A1	10/22/2003	Europe (corresponding to U.S. Application 10/608,032)		
PT	BG	1 359 608 A1	11/05/2003	Europe		
PT	BH	WO 02/50506 A1	06/27/2002	WIPO (w/ English abstract)	x	
				<input checked="" type="checkbox"/> Additional References sheet(s) attached		
Examiner 				Date Considered <i>10-17-04</i>		

\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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SHEET 2 OF 2

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY DOCKET NO. 219587US90	SERIAL NO. 10/072,866
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT Masato HAMATANI, et al.		
		FILING DATE February 12, 2002	GROUP 2851	

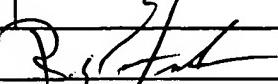
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

<i>RX</i>	AAA	Winter 1998 MICROLITHOGRAPHY WORLD pages 11-20 Authors: Donis G. Flagello and Bernd Geh Title: "The influence of lens aberrations in lithography"
<i>PJ</i>	AAB	Journal of Vacuum Science & Technology B: Microelectronics Processing and Phenomena, American Vacuum Society, New York, NY, US, vol. 16, no. 6, November 1998 (1998-11) pages 3435-3439 Authors: K. Goldberg, et al. Title: "High-accuracy interferometry of extreme ultraviolet lithographic optical system"
<i>PJ</i>	AAC	SPIE Microlithography Seminar, pages 1-14 Authors: Donis G. Flagello, et al. Title: "TOWARDS A COMPREHENSIVE CONTROL OF FULL-FIELD IMAGE QUALITY IN OPTICAL PHOTOLITHOGRAPHY"
	AAD	
	AAE	
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Examiner

Date Considered

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LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Masato HAMATANI, et al.			
				FILING DATE February 12, 2002	GROUP 2851		
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
PT	AA	5,807,647	09/15/1998	K. HASHIMOTO			
PT	AB	5,321,493	06/14/1994	K. KAMON			
PT	AC	4,786,166	11/22/1988	C. G. KROKO			
	AD						
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	AF						
	AG						
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	AJ						
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	AM						
	AN						
<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
PT	AO	0 267 721	05/18/1988	EUROPE	YES		NO
PT	AP	0 338 200	10/25/1989	EUROPE			
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	AR						
	AS						
	AT						
	AU						
	AV						
<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
	AW						
	AX						
	AY						
	AZ						<input type="checkbox"/> Additional References sheet(s) attached
Examiner 				Date Considered 10-17-04			
<small>*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							